ELSEVIER

Journal of Non-Crystalline Solids 191 (1995) 347–349

JOURNAL OF NON-CRYSTALLINE SOLIDS

Author index

Acharya, K.V., see Murugavel, S. 191 (1995) 327
Alves, O.L., see Cuevas, R.F. 191 (1995) 107
Ang, S.S., see Ranade, R.M. 191 (1995) 331
Aranha, N., see Cuevas, R.F. 191 (1995) 107
Asokan, S., see Murugavel, S. 191 (1995) 327

Barbosa, L.C., see Cuevas, R.F. 191 (1995) 107
Baribeau, J.M., see Laaziri, K. 191 (1995) 193
Barz, A., see Meyer, K. 191 (1995) 71
Bassanese, E., see Popovic, P. 191 (1995) 184
Bentley, J.L., see Inman, J.M. 191 (1995) 209
Bhatia, K.L., see Singh, P. 191 (1995) 146
Bienenstock, A., see Fernández van Raap, M.B. 191 (1995) 155
Boysen, H., see Zotov, N. 191 (1995) 124
Briois, V., C.V. Santilli, S.H. Pulcinelli and G.E.S. Brito, EXAFS and XRD analyses of the structural evolutions involved during drying of SnO_2 hydrogels 191 (1995) 17
Brito, G.E.S., see Briois, V. 191 (1995) 17
Brow, R.K., D.R. Tallant, S.T. Myers and C.C. Phifer, The short-range structure of zinc polyphosphate glass 191 (1995) 45
Brown, W.D., see Ranade, R.M. 191 (1995) 331
Buining, P.A., see Vogels, R.J.M.J. 191 (1995) 38
Burggraaf, A.J., see de Lange, R.S.A. 191 (1995) 1

Cavalieri, A.L., see Galliano, P.G. 191 (1995) 311
Cesar, C.L., see Cuevas, R.F. 191 (1995) 107
Chen, Q., see Wang, Z. 191 (1995) 132
Cheng, Y.Y., see Karis, T.E. 191 (1995) 293
Cuevas, R.F., L.C. Barbosa, A.M. de Paula, Y. Liu, V.C.S. Reynoso, O.L. Alves, N. Aranha and C.L. Cesar, Preparation and characterization of tellurium oxide based glass: Li_2O–TiO_2–TeO_2 system 191 (1995) 107
Czymai, A. and G.H. Frischat, A method to determine concentration–distance profiles of corroded glass fibers 191 (1995) 138

De Lange, R.S.A., J.H.A. Hekkink, K. Keizer and A.J. Burggraaf, Polymeric-silica-based sols for membrane modification applications: sol–gel synthesis and characterization with SAXS 191 (1995) 1
De Paula, A.M., see Cuevas, R.F. 191 (1995) 107
Dingwell, D., see Zotov, N. 191 (1995) 124
Dinolova, E., see Mihailova, B. 191 (1995) 79
Dupuis, V., see Paillard, V. 191 (1995) 174

Eason, R.W., see Gill, D.S. 191 (1995) 321
Efimov, O.M. and A.M. Mekryukov, Investigation of energy structure of lead silicate glasses by non-linear absorption spectroscopy technique 191 (1995) 94

Fernández van Raap, M.B., M.J. Regan and A. Bienenstock, Evidence of phase separation in amorphous Fe_xSi_{1-x} films 191 (1995) 155
Ferrari, M., L.M. Gratton, A. Maddalena, M. Montagna and C. Tosello, Preparation of silver nanoparticles in silica films by combined thermal and electron-beam deposition 191 (1995) 101
Frischat, G.H., see Czymai, A. 191 (1995) 138
Fukunaga, J., see Wakasugi, T. 191 (1995) 238
Furlan, J., see Popovic, P. 191 (1995) 184

Galliano, P.G., A.L. Cavalieri and J.M. Porto López, A study by density measurements and indentation tests of a calcium silicophosphate bioactive glass with different MgO or SrO contents 191 (1995) 311
Garrido, J., see Gomez, F.J. 191 (1995) 164
Gendler, P.L., see Karis, T.E. 191 (1995) 293
Gervais, F., see Hauret, G. 191 (1995) 85
Geus, J.W., see Vogels, R.J.M.J. 191 (1995) 38
Gill, D.S., R.W. Eason, C. Zaldo, H.N. Rutt and N.A. Vainos, Characterisation of Ga–La–S chalcogenide glass thin-film optical waveguides, fabricated by pulsed laser deposition 191 (1995) 321
Gomez-Aleixandre, C., see Gomez, F.J. 191 (1995) 164
Gomez, F.J., J. Martinez, J. Garrido, C. Gomez-Aleixandre and J. Piqueras, Amorphous SiC layers deposited by electron cyclotron resonance plasma: spectroscopic ellipsometric measurements 191 (1995) 164
Gratton, L.M., see Ferrari, M. 191 (1995) 101

Hauret, G., Y. Vaills, T. Parot-Rajaona, F. Gervais, D. Mas and Y. Luspin, Dynamic behaviour of $(1-x)SiO_2$–$0.5xM_2O$ glasses (M = Na, Li) investigated by infrared and Brillouin spectroscopies 191 (1995) 85
Hekkink, J.H.A., see de Lange, R.S.A. 191 (1995) 1
Houde-Walter, S.N., see Inman, J.M. 191 (1995) 209
Humbert, B., Estimation of hydroxyl density at the surface of pyrogenic silicas by complementary NMR and Raman experiments 191 (1995) 29

Ibrahim, F., J.I.B. Wilson and P. John, Photo-oxidation of a-Si:C:H studied by in situ XPS 191 (1995) 200
Inman, J.M., J.L. Bentley and S.N. Houde-Walter, Modeling ion-exchanged glass photonics: the modified quasi-chemical diffusion coefficient 191 (1995) 209

Jansen, J.B.H., see Vogels, R.J.M.J. 191 (1995) 38
Jianrong, Q., see Osaka, A. 191 (1995) 339
John, P., see Ibrahim, F. 191 (1995) 200

Kanjilal, D., see Singh, P. 191 (1995) 146
Karis, T.E., S.J. Kim, P.L. Gendler and Y.Y. Cheng, Organic monomeric glass formation by substituted ethylenediamine 191 (1995) 293
Kawamura, K., see Okuno, M. 191 (1995) 249
Keizer, K., see de Lange, R.S.A. 191 (1995) 1
Kim, S.J., see Karis, T.E. 191 (1995) 293
Kishore, N., see Singh, P. 191 (1995) 146
Kloprogge, J.T., see Vogels, R.J.M.J. 191 (1995) 38
Konstantinov, L., see Mihailova, B. 191 (1995) 79

Laaziri, K., S. Roorda and J.M. Baribeau, Density of amorphous Si_xGe_{1-x} alloys prepared by high-energy ion implantation 191 (1995) 193
Ledue, D. and J. Teillet, Critical temperature of the non-frustrated ferromagnetic Ising model on the quasiperiodic octagonal tiling 191 (1995) 216
Li, Y., see Wang, Z. 191 (1995) 132
Liu, Y., see Cuevas, R.F. 191 (1995) 107
Luspin, Y., see Hauret, G. 191 (1995) 85

Maddalena, A., see Ferrari, M. 191 (1995) 101
Malik, S.K., see Singh, P. 191 (1995) 146
Marchal, E., Erratum. A new way of interpreting thermally stimulated depolarization currents of polymers using the coupling model in a broad temperature range (J. Non-Cryst. Solids 172–174 (1994) 902–906) 191 (1995) 346
Martinez, J., see Gomez, F.J. 191 (1995) 164
Mas, D., see Hauret, G. 191 (1995) 85
Meaudre, M., see Paillard, V. 191 (1995) 174
Meaudre, R., see Paillard, V. 191 (1995) 174
Mekryukov, A.M., see Efimov, O.M. 191 (1995) 94
Melinon, P., see Paillard, V. 191 (1995) 174
Meyer, K., A. Barz and D. Stachel, Effects of atmospheric humidity on the infrared reflectivity of vitreous P_2O_5 and ultraphosphate glasses 191 (1995) 71
Mihailova, B., L. Konstantinov and E. Dinolova, Cluster-approximation modelling of infrared and Raman spectra of crystalline and vitreous $CaSiO_3$ 191 (1995) 79
Miura, Y., see Osaka, A. 191 (1995) 339
Mochida, N., see Sekiya, T. 191 (1995) 115
Montagna, M., see Ferrari, M. 191 (1995) 101
Murugavel, S., K.V. Acharya and S. Asokan, Pressure-induced metallization in Al–As–Te glasses 191 (1995) 327
Myers, S.T., see Brow, R.K. 191 (1995) 45

Nesheva, D., see Vateva, E. 191 (1995) 205
Nozawa, Y., see Wakasugi, T. 191 (1995) 238

Ogata, Y., see Uchino, T. 191 (1995) 56
Okuno, M. and K. Kawamura, Molecular dynamics calculations for $Mg_3Al_2Si_3O_{12}$ (pyrope) and $Ca_3Al_2Si_3O_{12}$ (grossular) glass structures 191 (1995) 249
Osaka, A., Q. Jianrong, Y. Miura and T. Yao, EXAFS of germanium in glasses of the GeO_2–TeO_2 system 191 (1995) 339
Ota, R., see Wakasugi, T. 191 (1995) 238

Paillard, V., M. Meaudre, P. Melinon, V. Dupuis, J.P. Perez, S. Vignoli, A. Perez and R. Meaudre, DC conduction in diamond-like carbon films obtained by low-energy cluster beam deposition 191 (1995) 174
Park, S.Y., R.A. Weeks and R.A. Zuhr, Bi- or multi-modal distribution of ion-implanted bismuth in fused silica 191 (1995) 281
Parot-Rajaona, T., see Hauret, G. 191 (1995) 85
Perez, A., see Paillard, V. 191 (1995) 174
Perez, J.P., see Paillard, V. 191 (1995) 174
Phifer, C.C., see Brow, R.K. 191 (1995) 45
Piqueras, J., see Gomez, F.J. 191 (1995) 164
Popovic, P., E. Bassanese, J. Furlan, F. Smole and I. Skubic, Internal and external characteristics in transient forward bias simulations of a-Si:H devices 191 (1995) 184
Porto López, J.M., see Galliano, P.G. 191 (1995) 311
Pulcinelli, S.H., see Briois, V. 191 (1995) 17

Ranade, R.M., S.S. Ang and W.D. Brown, Properties of fluorinated amorphous silicon-nitrogen–oxygen alloy (a-SiN_xO_y:H) deposited by plasma-enhanced chemical vapor deposition 191 (1995) 331
Regan, M.J., see Fernández van Raap, M.B. 191 (1995) 155
Reynoso, V.C.S., see Cuevas, R.F. 191 (1995) 107
Romano, C., see Zotov, N. 191 (1995) 124

Roorda, S., see Laaziri, K. 191 (1995) 193
Rutt, H.N., see Gill, D.S. 191 (1995) 321

Sansores, L.E. and A.A. Valladares, Amorphous clusters: the electronic structure of Ge clusters with B and Al impurities 191 (1995) 227
Santilli, C.V., see Briois, V. 191 (1995) 17
Sekiya, T., N. Mochida and A. Soejima, Raman spectra of binary tellurite glasses containing tri- or tetra-valent cations 191 (1995) 115
Seykens, D., see Vogels, R.J.M.J. 191 (1995) 38
Singh, M., see Singh, P. 191 (1995) 146
Singh, P., K.L. Bhatia, N. Kishore, M. Singh, S.K. Malik and D. Kanjilal, Doping of chalcogenide glassy semiconductor by implanting Ni ions 191 (1995) 146
Skubic, I., see Popovic, P. 191 (1995) 184
Smole, F., see Popovic, P. 191 (1995) 184
Soejima, A., see Sekiya, T. 191 (1995) 115
Sokolov, V.O., see Sulimov, V.B. 191 (1995) 260
Stachel, D., see Meyer, K. 191 (1995) 71
Sulimov, V.B. and V.O. Sokolov, Cluster modeling of the neutral oxygen vacancy in pure silicon dioxide 191 (1995) 260

Tallant, D.R., see Brow, R.K. 191 (1995) 45
Tanigami, Y., see Zhang, Z. 191 (1995) 304
Teillet, J., see Ledue, D. 191 (1995) 216
Terai, R., see Zhang, Z. 191 (1995) 304
Tosello, C., see Ferrari, M. 191 (1995) 101
Tu, C., see Wang, Z. 191 (1995) 132

Uchino, T. and Y. Ogata, Ab initio molecular orbital calculations on the electronic structure of phosphate glasses. Binary alkali metaphosphate glasses 191 (1995) 56

Vaills, Y., see Hauret, G. 191 (1995) 85
Vainos, N.A., see Gill, D.S. 191 (1995) 321
Valladares, A.A., see Sansores, L.E. 191 (1995) 227
Vateva, E. and D. Nesheva, Small-angle X-ray diffraction studies on interface sharpness of amorphous Se/CdSe superlattices 191 (1995) 205
Vignoli, S., see Paillard, V. 191 (1995) 174
Vogels, R.J.M.J., J.T. Kloprogge, P.A. Buining, D. Seykens, J.B.H. Jansen and J.W. Geus, The tridecameric aluminum complex as an appropriate precursor for fibrous boehmite: A ^{27}Al NMR study on the partial hydrolysis of aluminum sec-butoxide 191 (1995) 38

Wakasugi, T., R. Ota, Y. Nozawa and J. Fukunaga, Amorphous regions and crystallization behavior of rf-sputtered films in the B_2O_3–Na_2O–Al_2O_3 system 191 (1995) 238
Wang, Z., C. Tu, Y. Li and Q. Chen, The effects of Sn and Bi additions on properties and structure in Ge–Se–Te chalcogenide glass 191 (1995) 132
Weeks, R.A., see Park, S.Y. 191 (1995) 281
Wilson, J.I.B., see Ibrahim, F. 191 (1995) 200

Yanev, Y., see Zotov, N. 191 (1995) 124
Yao, T., see Osaka, A. 191 (1995) 339

Zaldo, C., see Gill, D.S. 191 (1995) 321
Zhang, Z., Y. Tanigami and R. Terai, Catalytic effect of acetylacetonates on gel formation of $CH_3SiO_{3/2}$ 191 (1995) 304
Zotov, N., H. Boysen, C. Romano, D. Dingwell and Y. Yanev, Neutron diffraction study of feldspar glasses. Mixed alkali effect 191 (1995) 124
Zuhr, R.A., see Park, S.Y. 191 (1995) 281

ELSEVIER

Journal of Non-Crystalline Solids 191 (1995) 350–352

JOURNAL OF NON-CRYSTALLINE SOLIDS

Subject index

Alkali Silicate Glasses
Brillouin Scattering, Infra-red Absorption 191 (1995) 85

Alumina
Glass Formation, Sputtering 191 (1995) 238

Amorphous Semiconductors
Density, Ion Irradiation 191 (1995) 193
Electrical Properties, Electronic Conductivity, Modelling 191 (1995) 184
Photoinduced Effects, XPS 191 (1995) 200

Auger Electron Spectroscopy
Electronic Conductivity, Infra-red Absorption, Nitrogen-Containing Glass, Plasma Deposition 191 (1995) 331

Brillouin Scattering
Alkali Silicate Glasses, Infra-red Absorption 191 (1995) 85

Carbon
Deposition Techniques, Electric Properties, Thin Films 191 (1995) 174

Chalcogenides
Interfaces, X-ray Diffraction 191 (1995) 205
Optical Waveguide, Thin Films 191 (1995) 321

Chalcogenide Glasses
Electrical Properties, Photoreceptor 191 (1995) 327
Glass Fibers, Raman Spectra 191 (1995) 132
Glasses Containing Transition Metal Ions, Ion Implantation, Semiconductors 191 (1995) 146

Clusters
Germanium, Hydrogen Effects, Theory 191 (1995) 227

Coordination
Density, Hardness, Oxides 191 (1995) 311

Crystallization
Polymers, Polymer Dynamics, Polymer Melt 191 (1995) 293

Defects
Modelling, Silica, Theory 191 (1995) 260
Non-linear Optics, Silicates 191 (1995) 94

Density
Amorphous Semiconductors, Ion Irradiation 191 (1995) 193
Coordination, Hardness, Oxides 191 (1995) 311

Deposition Techniques
Carbon, Electric Properties, Thin Films 191 (1995) 174

Diffusion
Gradient Index, Ion Exchange, Modelling 191 (1995) 209
Ion Implantation, Radiation Effects 191 (1995) 281

Electric Properties
Carbon, Deposition Techniques, Thin Films 191 (1995) 174

Electrical Properties
Amorphous Semiconductors, Electronic Conductivity, Modelling 191 (1995) 184
Chalcogenide Glasses, Photoreceptor 191 (1995) 327

Electronic Conductivity
Amorphous Semiconductors, Electrical Properties, Modelling 191 (1995) 184
Auger Electron Spectroscopy, Infra-red Absorption, Nitrogen-Containing Glass, Plasma Deposition 191 (1995) 331

Etching
Glass Fibers, Solutions, Surface Analysis 191 (1995) 138

EXAFS
Germanates, Structure 191 (1995) 339
Oxides, Sol–Gel Processes, X-ray Diffraction 191 (1995) 17

Fluorescence Spectra
Optical Properties, Sol–Gel Processes 191 (1995) 304

Germanates
EXAFS, Structure 191 (1995) 339

Germanium
Clusters, Hydrogen Effects, Theory 191 (1995) 227

Glass Fibers
Chalcogenide Glasses, Raman Spectra 191 (1995) 132
Etching, Solutions, Surface Analysis 191 (1995) 138

Glass Formation
Alumina, Sputtering 191 (1995) 238

Glasses Containing Transition Metal Ions
Chalcogenide Glasses, Ion Implantation, Semiconductors 191 (1995) 146
Phase Transition, Small Angle X-ray Scattering, Thin Films 191 (1995) 155

Gradient Index
Diffusion, Ion Exchange, Modelling 191 (1995) 209

Hardness
Coordination, Density, Oxides 191 (1995) 311

Hydrogen Effects
Clusters, Germanium, Theory 191 (1995) 227

Hydrogenation
Infra-red Absorption, Nuclear Magnetic Resonance, Porosity, Sol–Gel Processes 191 (1995) 29

Infra-red Absorption
Alkali Silicate Glasses, Brillouin Scattering 191 (1995) 85
Auger Electron Spectroscopy, Electronic Conductivity, Nitrogen-Containing Glass, Plasma Deposition 191 (1995) 331
Hydrogenation, Nuclear Magnetic Resonance, Porosity, Sol–Gel Processes 191 (1995) 29
Modelling, Raman Spectra, Silicates 191 (1995) 79
Phosphates, Surface Reactions 191 (1995) 71

Interfaces
Chalcogenides, X-ray Diffraction 191 (1995) 205

Ion Exchange
Diffusion, Gradient Index, Modelling 191 (1995) 209

Ion Implantation
Chalcogenide Glasses, Glasses Containing Transition Metal Ions, Semiconductors 191 (1995) 146
Diffusion, Radiation Effects 191 (1995) 281

Ion Irradiation
Amorphous Semiconductors, Density 191 (1995) 193

Light Scattering
Non-linear Optics, Raman Spectra 191 (1995) 101

Magnetic Properties
Modelling, Theory 191 (1995) 216

Medium-Range Order
Phosphates, Theory 191 (1995) 56

Membranes
Porosity, Sol–Gel Processes 191 (1995) 1

Microstructure
Nuclear Magnetic Resonance, Sol–Gel Precursors 191 (1995) 38

Mixed-Alkali Effect
Neutron Diffraction, Oxides 191 (1995) 124

Modelling
Amorphous Semiconductors, Electrical Properties, Electronic Conductivity 191 (1995) 184
Defects, Silica, Theory 191 (1995) 260
Diffusion, Gradient Index, Ion Exchange 191 (1995) 209
Infra-red Absorption, Raman Spectra, Silicates 191 (1995) 79
Magnetic Properties, Theory 191 (1995) 216

Molecular Dynamics
Silicates 191 (1995) 249

Neutron Diffraction
Mixed-Alkali Effect, Oxides 191 (1995) 124

Nitrogen-Containing Glass
Auger Electron Spectroscopy, Electronic Conductivity, Infra-red Absorption, Plasma Deposition 191 (1995) 331

Non-linear Optics
Defects, Silicates 191 (1995) 94
Light Scattering, Raman Spectra 191 (1995) 101
Optical Properties, Oxides 191 (1995) 107

Nuclear Magnetic Resonance
Hydrogenation, Infra-red Absorption, Porosity, Sol–Gel Processes 191 (1995) 29
Microstructure, Sol–Gel Precursors 191 (1995) 38
Phosphates, Structure 191 (1995) 45

Optical Properties
Fluorescence Spectra, Sol–Gel Processes 191 (1995) 304
Non-linear Optics, Oxides 191 (1995) 107

Optical Waveguide
Chalcogenides, Thin Films 191 (1995) 321

Oxides
Coordination, Density, Hardness 191 (1995) 311
EXAFS, Sol–Gel Processes, X-ray Diffraction 191 (1995) 17
Mixed-Alkali Effect, Neutron Diffraction 191 (1995) 124
Non-linear Optics, Optical Properties 191 (1995) 107
Raman Spectra, Structure 191 (1995) 115

Phase Transition
Glasses Containing Transition Metal Ions, Small Angle X-ray Scattering, Thin Films 191 (1995) 155

Phosphates
Infra-red Absorption, Surface Reactions 191 (1995) 71
Medium-Range Order, Theory 191 (1995) 56
Nuclear Magnetic Resonance, Structure 191 (1995) 45

Photoinduced Effects
Amorphous Semiconductors, XPS 191 (1995) 200

Photoreceptor
Chalcogenide Glasses, Electrical Properties 191 (1995) 327

Plasma Deposition
Auger Electron Spectroscopy, Electronic Conductivity, Infra-red Absorption, Nitrogen-Containing Glass 191 (1995) 331
Silicon Carbide, Thin Films 191 (1995) 164

Polymers
Crystallization, Polymer Dynamics, Polymer Melt 191 (1995) 293

Polymer Dynamics
Crystallization, Polymers, Polymer Melt 191 (1995) 293

Polymer Melt
Crystallization, Polymers, Polymer Dynamics 191 (1995) 293

Porosity
Hydrogenation, Infra-red Absorption, Nuclear Magnetic Resonance, Sol–Gel Processes 191 (1995) 29
Membranes, Sol–Gel Processes 191 (1995) 1

Radiation Effects
Diffusion, Ion Implantation 191 (1995) 281

Raman Spectra
Chalcogenide Glasses, Glass Fibers 191 (1995) 132
Infra-red Absorption, Modelling, Silicates 191 (1995) 79
Light Scattering, Non-linear Optics 191 (1995) 101
Oxides, Structure 191 (1995) 115

Semiconductors
Chalcogenide Glasses, Glasses Containing Transition Metal Ions, Ion Implantation 191 (1995) 146

Silica
Defects, Modelling, Theory 191 (1995) 260

Silicates
Defects, Non-linear Optics 191 (1995) 94
Infra-red Absorption, Modelling, Raman Spectra 191 (1995) 79
Molecular Dynamics 191 (1995) 249

Silicon Carbide
Plasma Deposition, Thin Films 191 (1995) 164

Small Angle X-ray Scattering
Glasses Containing Transition Metal Ions, Phase Transition, Thin Films 191 (1995) 155

Sol–Gel Precursors
Microstructure, Nuclear Magnetic Resonance 191 (1995) 38

Sol–Gel Processes
EXAFS, Oxides, X-ray Diffraction 191 (1995) 17
Fluorescence Spectra, Optical Properties 191 (1995) 304
Hydrogenation, Infra-red Absorption, Nuclear Magnetic Resonance, Porosity 191 (1995) 29
Membranes, Porosity 191 (1995) 1

Solutions
Etching, Glass Fibers, Surface Analysis 191 (1995) 138

Sputtering
Alumina, Glass Formation 191 (1995) 238

Structure
EXAFS, Germanates 191 (1995) 339
Nuclear Magnetic Resonance, Phosphates 191 (1995) 45
Oxides, Raman Spectra 191 (1995) 115

Surface Analysis
Etching, Glass Fibers, Solutions 191 (1995) 138

Surface Reactions
Infra-red Absorption, Phosphates 191 (1995) 71

Theory
Clusters, Germanium, Hydrogen Effects 191 (1995) 227
Defects, Modelling, Silica 191 (1995) 260
Magnetic Properties, Modelling 191 (1995) 216
Medium-Range Order, Phosphates 191 (1995) 56

Thin Films
Carbon, Deposition Techniques, Electric Properties 191 (1995) 174
Chalcogenides, Optical Waveguide 191 (1995) 321
Glasses Containing Transition Metal Ions, Phase Transition, Small Angle X-ray Scattering 191 (1995) 155
Plasma Deposition, Silicon Carbide 191 (1995) 164

XPS
Amorphous Semiconductors, Photoinduced Effects 191 (1995) 200

X-ray Diffraction
Chalcogenides, Interfaces 191 (1995) 205
EXAFS, Oxides, Sol–Gel Processes 191 (1995) 17